



AVX BME X7R Capacitors for Space

October 2016

John Marshall, Technical Manager

Michael Conway, Product Manager

AVX Ltd. - Ceramics Division

Hillman's Way, Coleraine, N Ireland, UK

Email: michael.conway@eur.avx.com

Phone +44 28 7034 0672



QPL BME Capacitors for Space/Mil Applications

■ Contents

- BME Capacitors for Space / Military – Reliability and Performance data.
- Space grade BME Capacitor Structure and Micro-sectional analysis
- BME planned developments and opportunities
- Conclusion

Space / Military – Reliability and Performance data

■ Space and Military Grade BME QPL parts

- *Select Hi CV materials* with a proven quality - reliability heritage in field performance (Normally ≥ 5 years history required)
- *Conservative designs* – no changes allowed once qualified/approved
- *Stable electrical parameters* - (ESR, VC, TC, VBD etc)
- *Controlled Material and Process* - restricted by ESCC PID controls
- *External qualification requirements* - ESCC, NASA, Mil approvals needed plus Audit systems
- *100% Acoustic Microscopy* Inspection
- *100% Burn In* with defined failure levels
- Lot C of C/Data packs

Space Electrical Characteristics Data

Stable as Material and Design rules are defined in PID

300904104225MX Electrical Characteristics Data

(1206 25V X7R 2.2 μ F \pm 20%)



Data in this document is subject to change without notice.

Dimensions



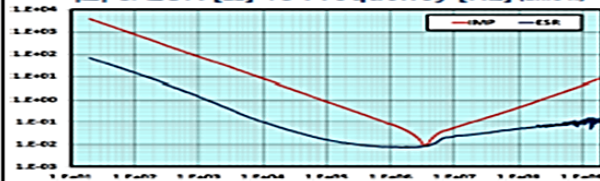
	millimetres (inches)
L	3.20 \pm 0.20 (0.126 \pm 0.008)
W	1.60 \pm 0.20 (0.063 \pm 0.008)
T	1.75 max. (0.069 max.)

Basic Specifications

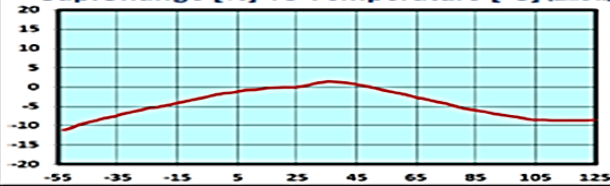
Item	Unit	Spec.	Conditions
Capacitance	μ F	1.76 to 2.64	@ 1 kHz, 1 V _{rms}
DF	%	3.0 max.	@ 1 kHz, 1 V _{rms}
IR	M Ω	455 min.	@ 25 V _{DC} , t _a = 120 s
D/WV	V _{DC}	75 V _{DC}	@ I _a \leq 50 mA, t _a \leq 5 s

Operating Temperature	-55 °C to +125 °C
Temp. Characteristic	X7R (\pm 15%)
Failure Rate	N/A
Termination	FLEXITERM / On (100% made)

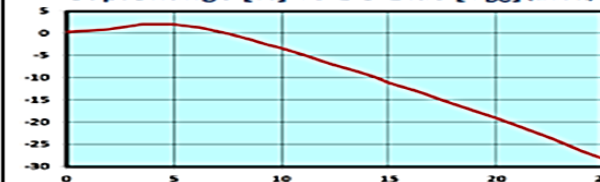
|Z| & ESR [Ω] vs Frequency [Hz] (axle x)



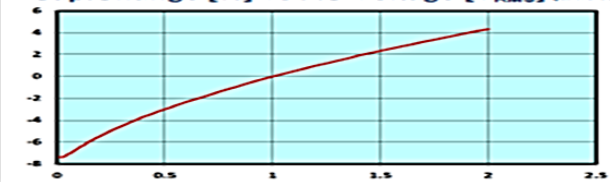
Cap.Change [%] vs Temperature [°C] (axle x)



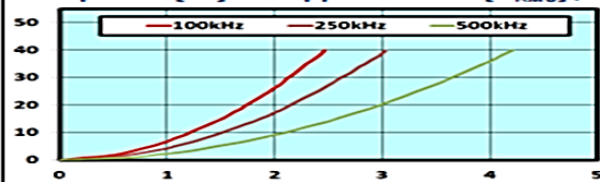
Cap.Change [%] vs DC Bias [V_{DC}] (axle x)



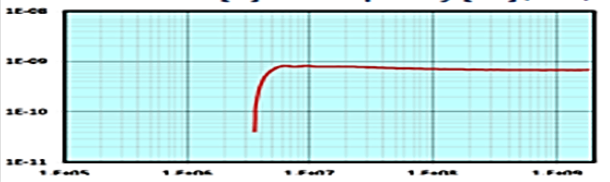
Cap.Change [%] vs AC Voltage [V_{RMSE}] (axle x)



Temp.Rise [°C] vs Ripple Current [A_{RMSE}] (axle x)



Inductance [H] vs Frequency [Hz] (axle x)



Updated: 23 July 2015



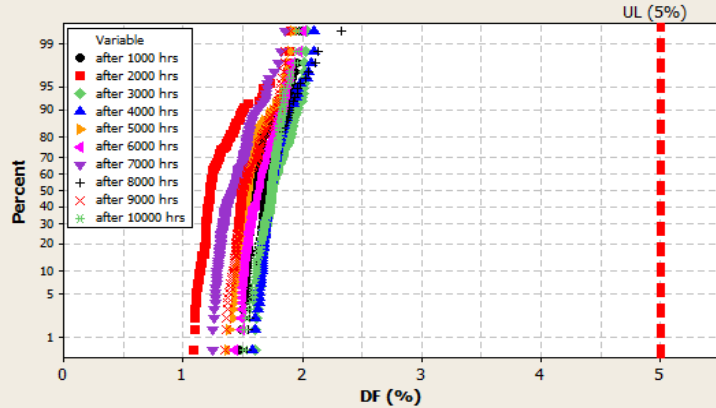
Page: 1 - of 1

Long Term Standard Life Testing 10,000hrs for Aerospace Corp .

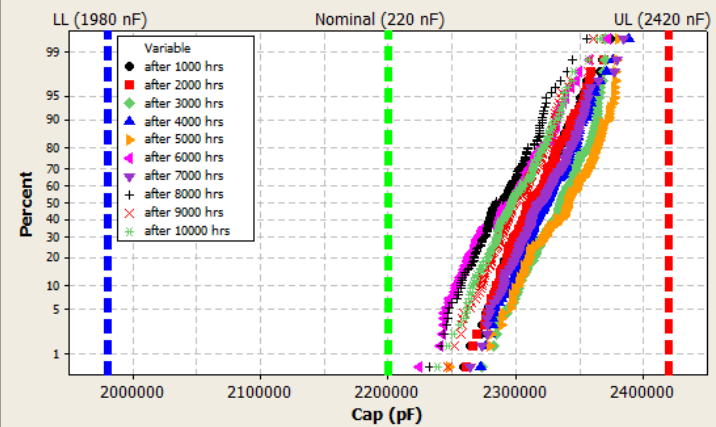
	Life Testing 2 x Rated Voltage @ 125 Deg C . Sample Size 125 pcs									
AVX Part number	1,000 Hrs	2,000 Hrs	3,000 Hrs	4,000 Hrs	5,000 Hrs	6,000 Hrs	7,000 Hrs	8,000 Hrs	9,000 Hrs	10,000 Hrs
18123C825K	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
06033C184K	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
12105C105K	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
12065C105K	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
08051C104K	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
18121C225K	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS

Long Term Life 10,000 hr Parametric Data 1812 100V 2.2uF

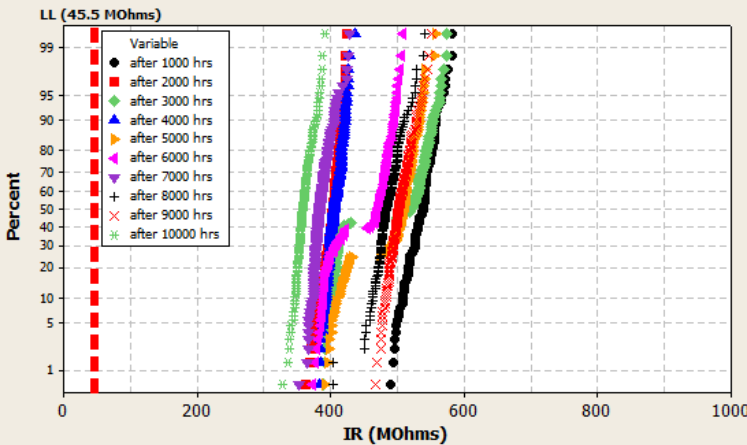
Probability Plot of 18121C225KECQQT DF after 1,000 - 10,000 hrs test
Normal



Probability Plot of 18121C225KECQQT Cap after 1,000 - 10,000 hrs test



Probability Plot of 18121C225KECQQT IR after 1,000 - 10,000 hrs test



DPA section Space BME 1812 100v 2.2uF



131 Active Layers @ 18um per layer (Unfired)

High Acceleration Life Testing, HALT

- A number of BME part numbers have been tested on a HALT system to calculate the field life time by determining the Voltage exponent, N , and the Energy of Activation, E_a .

Part Number	Conditions		
12065C105	270 Volts 150 Deg C	285 Volts 150 Deg C	290 Volts 150 Deg C
12065C105	250 Volts 150 Deg C	250 Volts 155 Deg C	250 Volts 165 Deg C
12105C105	365 Volts 150 Deg C	370 Volts 150 Deg C	380 Volts 150 Deg C
12105C105	350 Volts 150 Deg C	350 Volts 155 Deg C	350 Volts 165 Deg C

Acceleration Factors

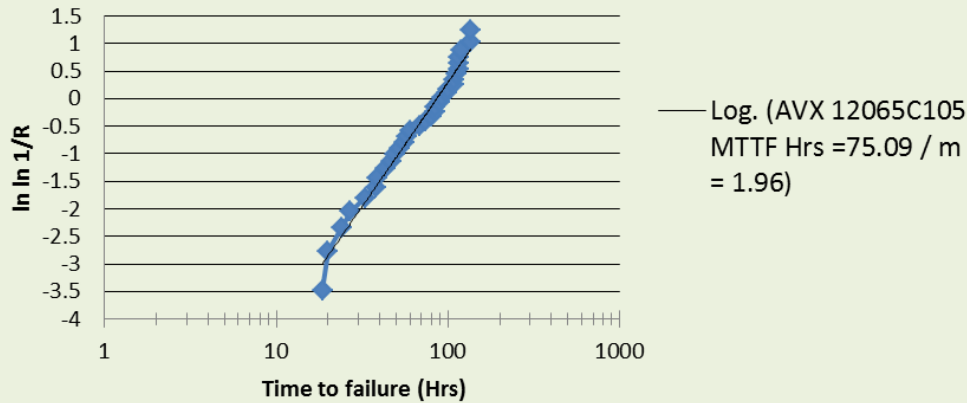
The acceleration model used was the Propokowice and Vaskas, P – V model

Part number	Voltage Exponent	Energy of activation	MTTF (Yrs) 85 Deg C 1 x RV	MTTF (Yrs) 85 Deg C 0.5 x RV	MTTF (Yrs) 125 Deg C 0.5 x RV
12105C105	8.17	1.17	4.40E+06	1.27E+09	2.79E+07

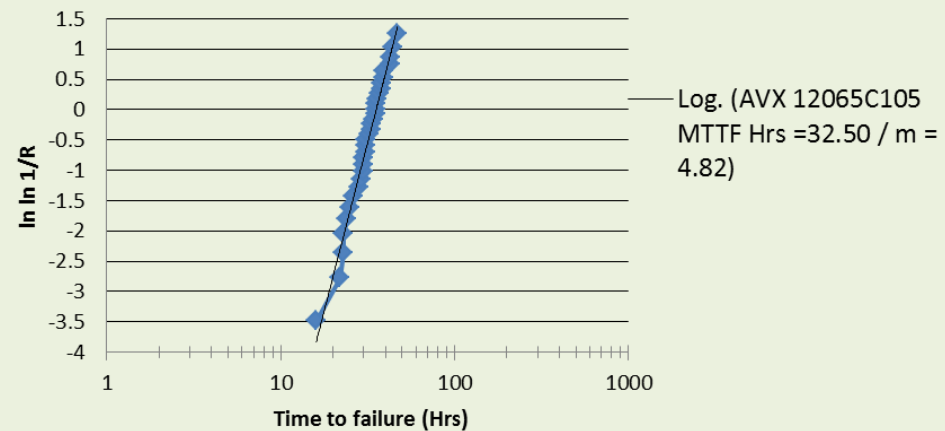


HALT WEIBULL PLOTS

**AVX 12065C105 Weibull plot 270 Volts @
150 Deg C**



**AVX 12065C105 Weibull plot 250 Volts @
165 Deg C**



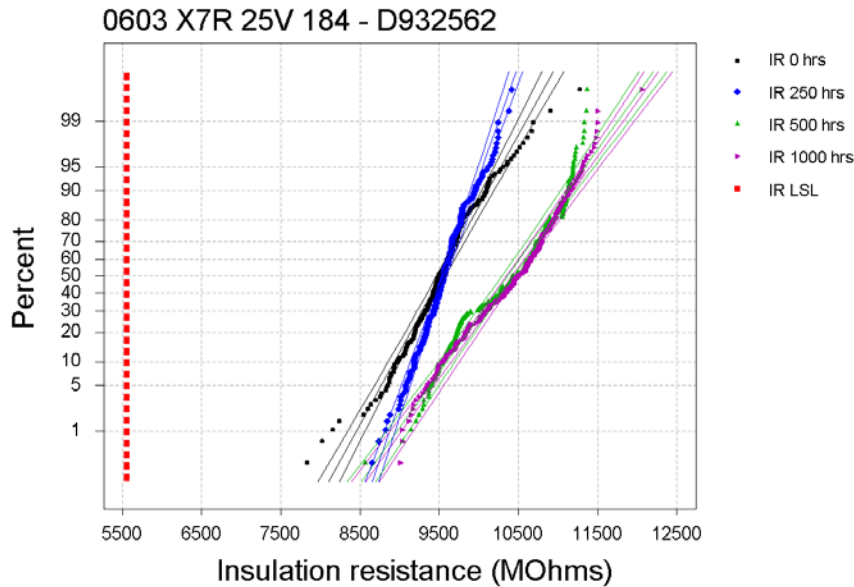
AVX Reliability on Space Level BME

Life testing at increased sample size and test voltage 3 X RV.
 Large sample size, Military and Space typically would be 40-120 pcs per part #

Part #	Capacitance (uF)	Rated Voltage (Vdc)	Fired Dielectric Thickness (microns)	Pcs on Life Test	Life Test Voltage (Vdc)	Life Test at 3X , 125°C		
						250 hrs	500 hrs	1,000 hrs
06033C184	0.18	25	6.0 - 6.5	500	75	0 / 500	0 / 500	0 / 500
18123C825	8.2	25	6.5 - 7.5	500	75	0 / 500	0 / 500	0 / 500

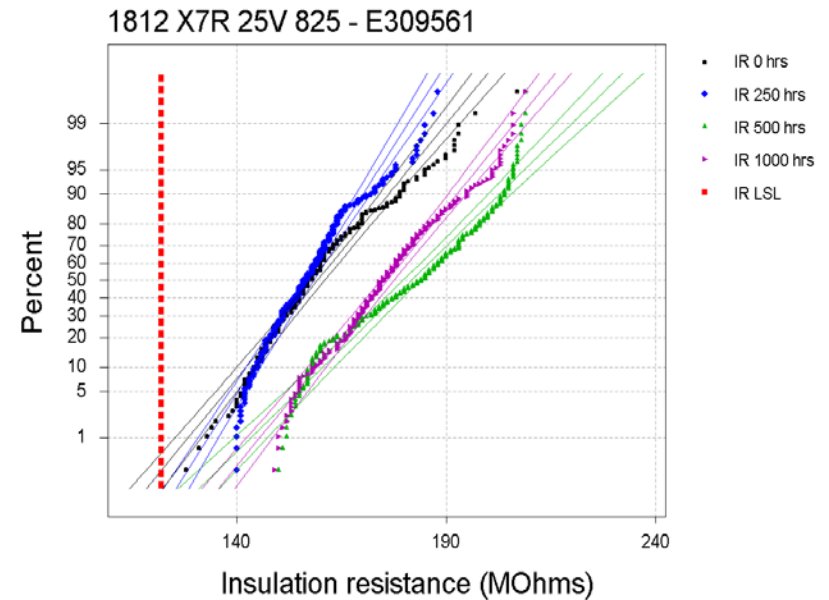
Accelerated 125°C Life Testing done at 3X rated, rather than Military and Space standard of 2X

Reliability on Space Level BME @ 3 x rated voltage to 1000hrs “Insulation Resistance” parametric data



**1812 8.2uF - no IR degradation
seen after 1000hrs at 3X rated,
125°C Life Testing**

**0603 180nF - no IR degradation
seen after 1000hrs at 3X rated,
125°C Life Testing**



Space and Military High Reliability Screening Systems BME and PME Screening

100% Sonoscan



NASA & Mil



100% Burn In



**ESA ,NASA &
Mil**

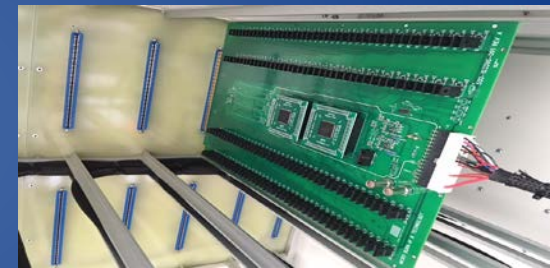


AVX
A KYOCERA GROUP COMPANY

<http://www.avx.com>

New Burn in System with "live" monitored IR

Scanner board

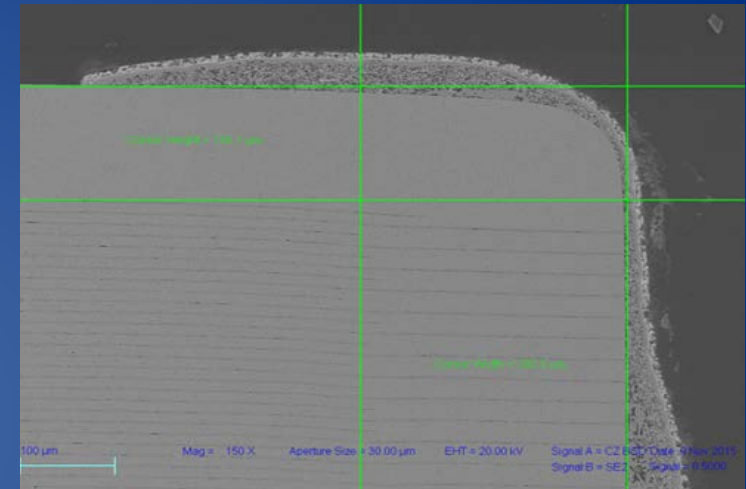
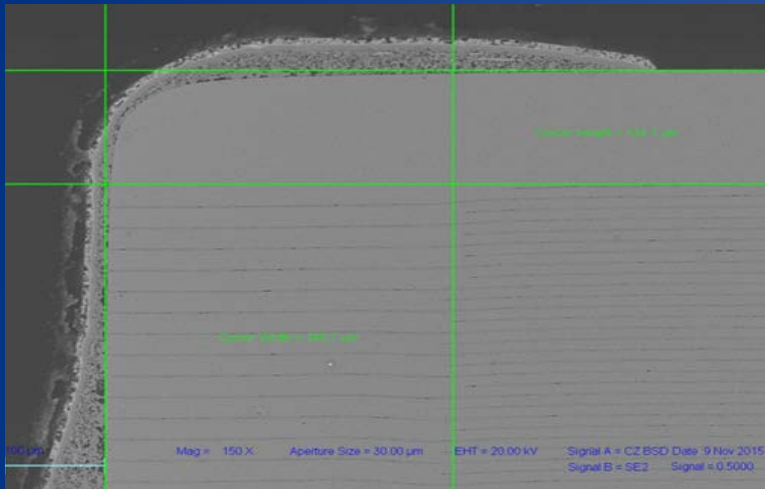


Test result screen

Micro Burn-In Technology, Inc. - Test Result Display

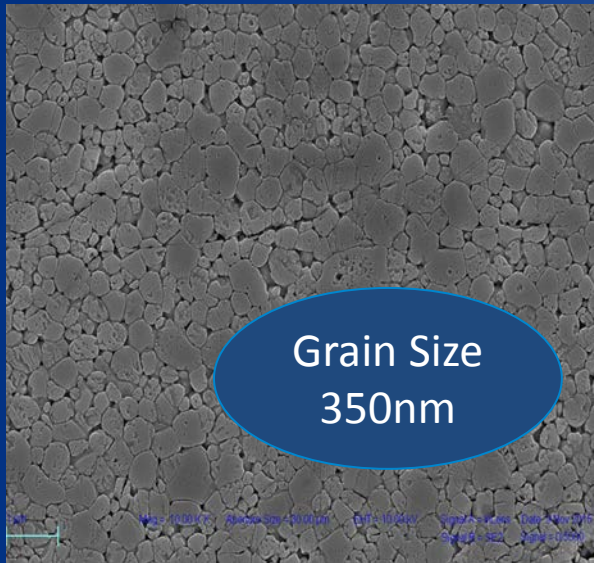
Zone	Slot	DUT	Lot Number	IR Values	IR Volt	IR Limit	Stress Volt	Stress Volt	Stress Limit	Test Time	Test Status
1	1	test 1	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	2	test 2	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	3	test 3	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	4	test 4	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	5	test 5	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	6	test 6	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	7	test 7	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	8	test 8	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	9	test 9	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	10	test 10	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	11	test 11	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	12	test 12	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	13	test 13	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	14	test 14	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	15	test 15	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	16	test 16	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	17	test 17	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	18	test 18	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	19	test 19	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	20	test 20	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	21	test 21	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	22	test 22	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	23	test 23	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	24	test 24	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	25	test 25	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	26	test 26	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	27	test 27	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	28	test 28	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	29	test 29	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	30	test 30	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	31	test 31	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	32	test 32	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	33	test 33	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	34	test 34	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	
1	35	test 35	2.456E-12	100	1E-10	4.789E-11	300	1E-09	11:10:50	In Progress	

Space – Military Grade Design 1210 50V 1uF Part SEM and Images



SIZE 1210	Dielectric Thickness	Cover Layer Thickness	Side Margin	End Margin
Average (microns) Specification	11.14	152.63	194.37	310.84
NASA >=	7.112	40.64	25.4	40.64
	PASS	PASS	PASS	PASS

Space – Military Grade design 1210 50V 1uF part SEM and Image for Grain Size Calculation



3.2.1.6 Average Grain Size: Capacitors shall be measured for average grain size as specified in paragraph 4.4.2.

3.2.2 BME Capacitor Acceptance Criterion. Capacitor samples, processed as specified in paragraphs 4.4.1 and 4.4.2 herein and meeting the requirements of paragraph 3.2.1 herein, shall meet Equation 1 as shown below:

$$F_t = 1 - R_t = 1 - \left[1 - \left(\frac{\bar{r}}{d} \right)^\alpha \right]^N < 0.00001 \text{ Equation 1}$$

Where \bar{r} is the measured average grain size, d is the average dielectric thickness, N is the total number of dielectric layers, $\alpha = 5$ for capacitors rated voltage $> 100V$ and $\alpha=6$ for capacitors rated voltage $\leq 100V$.

Size 1210 Inter-sections 5 samples	S Ave	Scale	Grain average	r	N	d	Diels Thick d ave	r ave / d ave	(r/d) power alpha	1-(r/d)power alpha
25	22.6	0.4	0.3539	0.3539	90	11.14	11.14	0.031776	0.0000000102938572657	0.9999999897061400000
22		alpha α								[1-(r/d)power α]powerN
20		6								0.99999990735529200000000000000000
23										1- [[1-(r/d)power α]powerN]
23										0.000000092644707794242700000000
NASA Spec. Compliant										TRUE

Material and Design Features for BME/PME X7R Space Grade ≤100V

	Commercial	PME Space	BME Space
Materials	Multiple Ceramics, / Ni Electrodes . No Sn/Pb, Supply chain control ?	Single Ceramic / Pd/Ag Electrode . No Change	Single Ceramic / Ni Electrode . No change
Design Range	Layers ≤ 800 , Dielectric Thickness 1 – 15 um ,	Layer ≤ 200 , Dielectric Thickness ≥ 25 um	Layer ≤ 300 , Dielectric Thickness 7 um - 18 um
Margin Cover	Small as possible ≥ 50 um	Thickness ≥ 100 um , Large as possible	Thickness ≥ 100 um , Large as possible
Voltage	4 – 100 v	Greater than 25 v	Current Range 16 – 100 volts
QA	Random Sampling , 3 rd Party suppliers	As per ESCC , 100 % Burn in , PID control, PDA limits	As per ESCC , 100 % Burn in , PID control, PDA limits

New Products BME : Enabling Technology

- Dispersion Technology

- Zeta Mill

- Fundamental Studies of Dopants

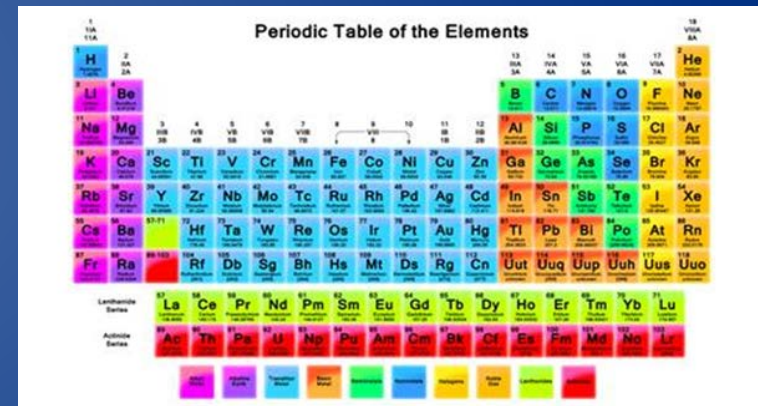
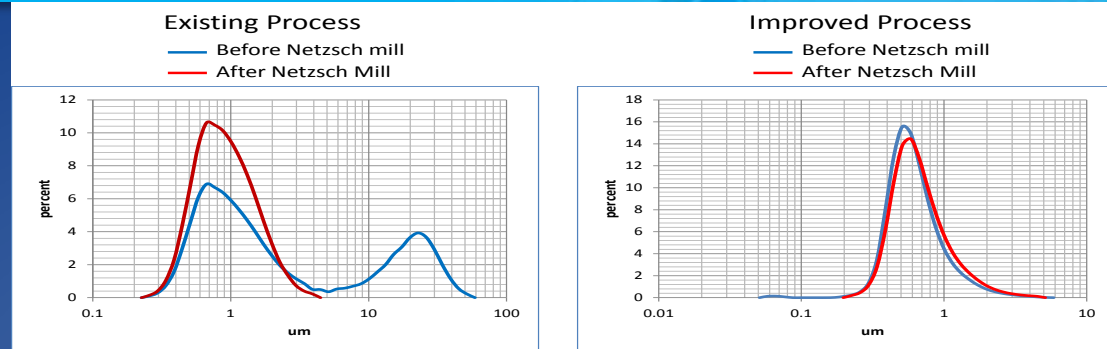
- Dy, Y, Yb, Hf, Tb, Sm, Ho, Er, Gd

- Reliability, Breakdown voltage, K

- BT Coatings

- Analytical

- High Temp EIS, Activation Energy, Slip Stability



BME Material Development Collaboration on STEM Analysis with Aerospace Corp



High Sensitivity / Sensitive but Unclassified (SBU) / Contains AVX Proprietary Information

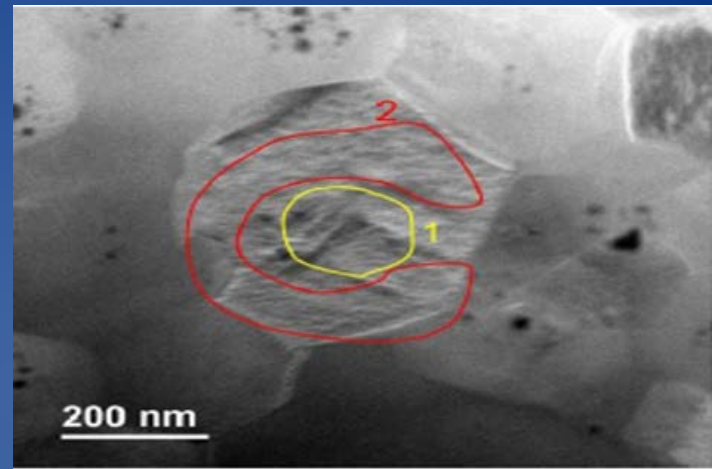
Chemical Analysis (TEM/EDS) on Base metal Electrode Multilayer Ceramic Capacitors (BME MLCCs) manufactured by AVX Corp.

Talin Ayvazian, Zachary Lingley, Miles Brodie and Brendan Foran

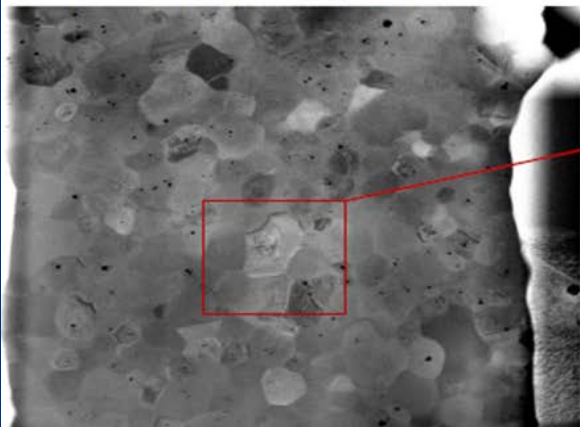
Electronic Materials and Devices Section
Physical Sciences Laboratory / ETG

March 10th, 2015 High Sensitivity/Contractor Proprietary Information [AVX Proprietary Information]
This material is intended to be accessed only by AVX staff who are US persons and foreign persons, and is limited release only to those persons. The material contains AVX proprietary information, which enabled the meaningful analysis of the electron microscopy performed at Aerospace.

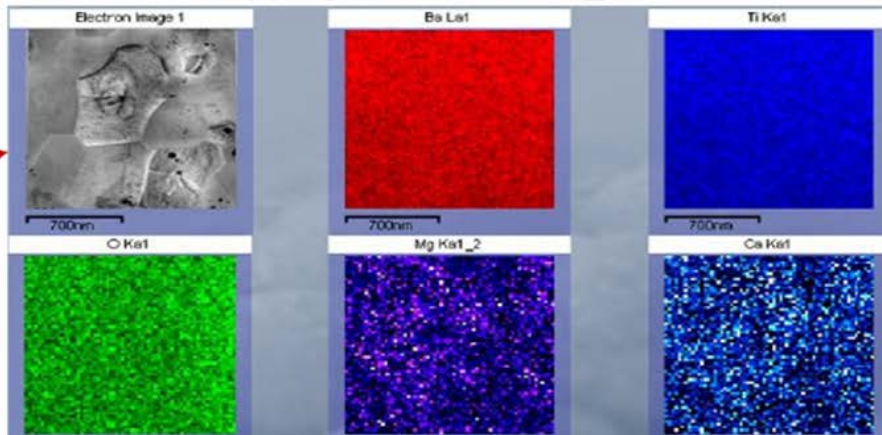
EDS spectrum compares chemical composition of core (1) and shell (2) regions.



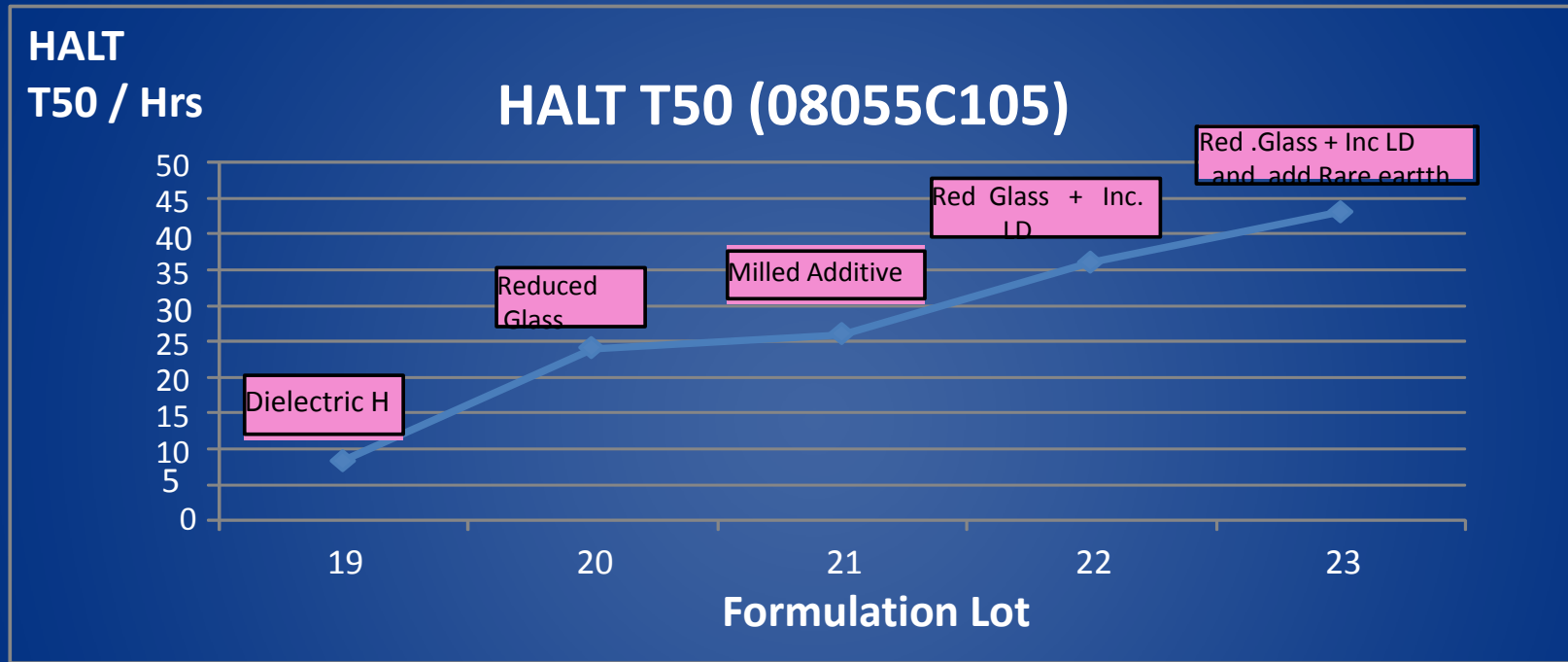
STEM image of AVX_Lot 7



Chemical mapping (EDS) of AVX_lot 7



Material contributors to improving the HALT Performance for Hi CV range extension



- Lower Glass enabled 50V qualification @ 6.5um dielectric thickness
- 4 x Fold Improvement in HALT for Dielectric H formulation achieved by
 - Increased Laydown
 - Pre Milling the additives
 - Adding/Increasing the rare earth %

AVX QPL 3009041 BME X7R Capacitor Range with Development ranges

Case Sizes		0402			0603			0805			1206			1210			1812			2220				
Code	Value	16/25v	50v	100v	16/25v	50v	100v	16/25v	50v	100v	16/25v	50v	100v	16/25v	50v	100v	16/25v	50v	100v	16/25v	50v	100v		
222	2.2nf																							
272	2.7nf																							
332	3.3nf																							
392	3.9nf																							
472	4.7nf																							
562	5.6nf																							
682	6.8nf																							
822	8.2nf																							
103	10nf																							
123	12nf																							
153	15nf																							
183	18nf																							
223	22nf																							
273	27nf																							
333	33nf																							
393	39nf																							
473	47nf																							
563	56nf																							
683	68nf																							
823	82nf																							
104	100nf																							
124	120nf																							
154	150nf																							
184	180nf																							
224	220nf																							
274	270nf																							
334	330nf																							
394	390nf																							
474	470nf																							
564	560nf																							
684	680nf																							
824	820nf																							
105	1µf																							
125	1.2µf																							
155	1.5µf																							
185	1.8µf																							
225	2.2µf																							
275	2.7µf																							
335	3.3µf																							
395	3.9µf																							
475	4.7µf																							
565	5.6µf																							
685	6.8µf																							
825	8.2µf																							
106	10µf																							
126	12µf																							
156	15µf																							
186	18µf																							
226	22µf																							

Key
 In development
 In production

U.S.A. NASA and MIL Approvals

- ❑ **NASA BME Spec released S-311-P-838 June 2015 . Approved April 2016**
Data pack includes - Cross-section , Grain Size , THB @rated Voltage etc
NASA QPLD listing completed Feb 2016 .

- ❑ **New Mil Prf Thin Spec 32535 released Sept 2015 . Approval Estimated June 2017**
 - Includes both BME and PME technology .
 - Coleraine and Czech facilities have “ Mil” audit completed May 2016 .
 - Manufacturing of qualification lots underway .
 - This will include 0402 and 2220 sizes with a max cap of 22uF .
 - Includes Low Inductance capacitors 0306 , 0508
 - Expect Mil Qualification to be completed through 1st half 2017
 - Need to complete the long term testing 4,000 hr life data

- ❑ **Gold termination parts on line for 12065C105K for USA customers .**
 - 2,000 hrs life tested completed and Passed Feb 2016 .
 - Life test 2,000hr data completed and Passed Feb 2016
 - Plan to qualify Gold range with Mil and ESCC ranges .

Conclusion

- AVX's Space BME X7R capacitors have clear differences set out from their Materials , Design , Processing and Testing than other BME, commercial, products to meet the ESCC/NASA/Mil Standards
- In addition, AVX has carried out extensive reliability testing
 - EPPL, ESCC 3009041 , NASA S311P838
 - Long term life testing 10,000 Hrs , 2 x RV @ 125 Deg C
 - HALT and Weibul Analysis
 - SEM and STEM analysis
- The Space BME range is under qualification testing for the Mil Prf 32535, including 4000 hrs life testing. Est June 2017
- Under evaluation is a range extension 0402 – 2220 e.g. 2220 50 volt 10 uf , 25 volt 22 uf .

Acknowledgement

- ESCC Evaluation Test Program 2008-2013

*Base Metal Electrode Ceramic Capacitors studies
(Contract No. 22484/09/NL/CP)*

AVX ESCC Approved Ceramic Capacitors

ESCC Approved AVX Ceramic Capacitor Ranges

AVX App Series	Ceramic Capacitor Type	Series Type
ESCC 3001030	Cap Ceramic fixed Type II	CH/CV Stacked
ESCC 3001034	Cap Ceramic fixed Type II High Volt , 1 Kv – 5 Kv	CH/CV Stacked
ESCC 3009034	Cap Ceramic fixed Type II High Volt , 1 Kv – 3 Kv	1812 - 1825
ESCC 3009	TPC Cap Ceramic Type I & II , 25 - 200 volt	0805 - 2220
ESCC 3009041	Cap Ceramic Type II,	0603 - 1812

AVX's NASA, European Space Agency and CECC Approved Ceramic Capacitor Products

European Space Agency
www.esa.int



Version 16.4





Michael Conway
Product Manager
michael.conway@eur.avx.com



Thank you